On antagonism between side-channel security and soft-error reliability in BNN inference engines
Lai, Xinhui; Lange, Thomas; **Balakrishnan, Aneesh**; Alexandrescu, Dan; **Jenihhin, Maksim** IFIP/IEEE 29th International
Conference on Very Large Scale Integration (VLSI-SoC) 2021 / p. 1-6 https://doi.org/10.1109/VLSI-SoC53125.2021.9606981